GE
Measurement & Control

X-ray System Upgrades

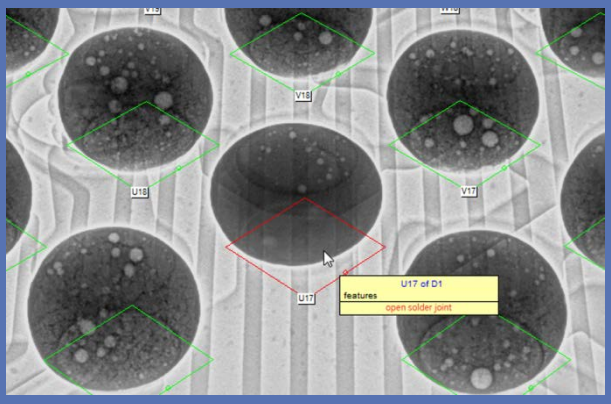
For phoenix microme|x and phoenix nanome|x inspection systems

Software

Windows® 7

Upgrade your X-ray inspection system and benefit from

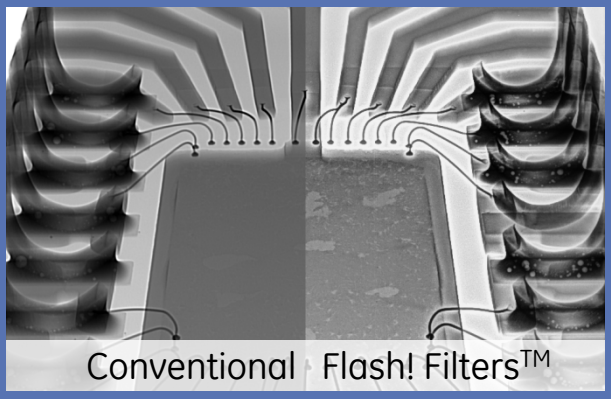
- Actual security requirements
- Easy to use interface
- Improved performance speed



x|act 9.0

2D X-ray inspection software

- Combining ease of use with excellence in intuitive X-ray inspection
- Advanced defect coverage
- Live CAD overlay with PAD-ID and inspection results – at any time and at any viewing angle



Flash! Filters™ - image optimization

- Enables faster, more reliable failure detection
- Automates the filtering process of all grey scales present in each X-ray image
- Leads to significant time savings and defect coverage improvements

GE imagination at work

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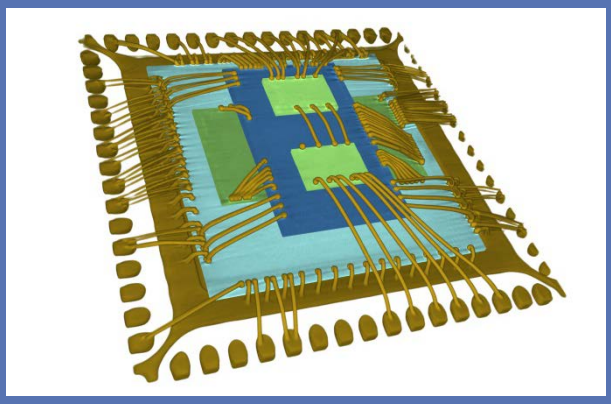
Hardware

High dynamic digital detectors

- High dynamic live imaging at full-resolution and corrections applied
- Endurance™ scintillator technology for best image quality due to minimized ghost image defect (lag)
- Temperature controlled for stable offsets over longer periods, enabling more consistent imaging and fewer calibrations



Computed Tomography (CT)

- High contrast flat panel CT
- Offers three-dimensional images of the interior, even of hidden parts, of a sample for detailed failure analysis
- High quality CT results available within a few minutes

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